INTEGRATED CIRCUITS

DATA SHEET

74F86Quad 2-input exclusive-OR gate

Product specification

1990 Feb 09

IC15 Data Handbook





Quad 2-input Exclusive-OR gate

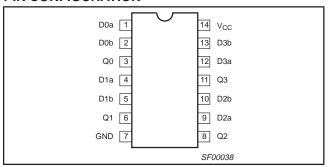
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FEATURE

• Industrial temperature range available (-40°C to +85°C)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F86	4.3ns	16.5mA

PIN CONFIGURATION



ORDERING INFORMATION

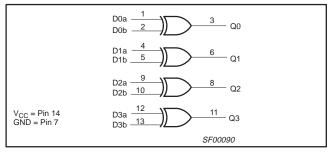
	O		
DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = 0^{\circ}C$ to +70°C	INDUSTRIAL RANGE V_{CC} = 5V $\pm 10\%$, T_{amb} = -40° C to +85 $^{\circ}$ C	PKG DWG #
14-pin plastic DIP	N74F86N	I74F86N	SOT27-1
14-pin plastic SO	N74F86D	I74F86D	SOT108-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dna, Dnb	Data inputs	1.0/1.0	20μA/0.6mA
Qn	Data output	50/33	1.0mA/20mA

NOTE:

LOGIC DIAGRAM



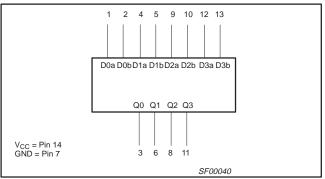
FUNCTION TABLE

INPL	JTS	OUTPUT
Dna	Dnb	Qn
L	L	L
L	Н	Н
Н	L	н
Н	Н	L

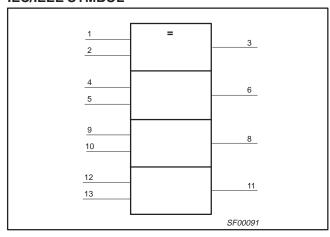
NOTES:

H = High voltage levelL = Low voltage level

LOGIC SYMBOL



IEC/IEEE SYMBOL



^{1.} One (1.0) FAST unit load is defined as: $20\mu A$ in the High state and 0.6mA in the Low state.

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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V _{CC}	Supply voltage		-0.5 to +7.0	V
V _{IN}	Input voltage		-0.5 to +7.0	V
I _{IN}	Input current		−30 to +5	mA
V_{OUT}	Voltage applied to output in High output state		–0.5 to V _{CC}	V
l _{OUT}	Current applied to output in Low output state		40	mA
_		Commercial range	0 to +70	°C
T _{amb}	Operating free-air temperature range	-40 to +85	°C	
T _{sta}	Storage temperature range	-65 to +150	°C	

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER			LIMITS		UNIT
STWIBOL	PARAMETER		MIN	NOM	MAX	UNII
V _{CC}	Supply voltage		4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V	
V _{IL}	Low-level input voltage			0.8	V	
I _{IK}	Input clamp current				-18	mA
I _{OH}	High-level output current				-1	mA
I _{OL}	Low-level output current			20	mA	
т.	Operating free-air temperature range	Commercial range	0		+70	°C
lamb	Operating nee-all temperature range	Industrial range	-40		+85	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDIT	IONS ¹		LIMITS		UNIT
					MIN	TYP ²	MAX	
V	Lligh lavel output voltage		V _{CC} = MIN, V _{IL} = MAX	$V_{CC} = MIN, V_{IL} = MAX$ ±10% V_{CC}				V
V _{OH}	V _{OH} High-level output voltage		V _{IH} = MIN, I _{OH} = MAX	±5%V _{CC}	2.7	3.4		V
M	Lave lavel autout valtage		$V_{CC} = MIN, V_{IL} = MAX$	±10%V _{CC}		0.30	0.50	V
V _{OL}	Low-level output voltage		$V_{IH} = MIN, I_{OL} = MAX$		0.30	0.50	V	
V _{IK}	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$		-0.73	-1.2	V	
I _I	Input current at maximum input vol	tage	$V_{CC} = MAX, V_I = 7.0V$			100	μΑ	
I _{IH}	High-level input current		$V_{CC} = MAX, V_I = 2.7V$			20	μΑ	
I _{IL}	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$			-0.6	mA	
Ios	Short-circuit output current ³		V _{CC} = MAX		-60		-150	mA
Icc	Supply current (total)		$V_{CC} = MAX$ D0a = GND, D0b = 4.5V			15	23	mA
		I _{CCL}	V _{CC} = MAX	$V_{IN} = 4.5V$		18	28	mA

NOTES:

- 1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- 2. All typical values are at $V_{CC} = 5V$, $T_{amb} = 25$ °C.
- 3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

Quad 2-input Exclusive-OR gate

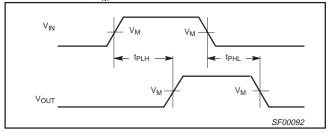
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AC ELECTRICAL CHARACTERISTICS

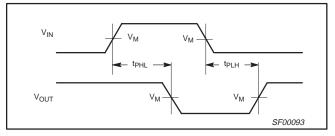
						LI	MITS			
SYMBOL	PARAMETER	TEST CONDITION	$V_{CC} = +5.0V$ $T_{amb} = +25^{\circ}C$ $C_{L} = 50pF$ $R_{L} = 500\Omega$			T _{amb} = 0°C C _L =	0V ± 10% C to +70°C 50pF 500Ω	V _{CC} = +5. T _{amb} = -40° C _L = R _L =	UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay Dna or Dnb to Qn (other input Low)	Waveform 1	3.0 3.0	4.0 4.2	5.5 5.5	3.0 3.0	6.5 6.5	3.0 2.5	7.0 8.0	ns
t _{PLH} t _{PHL}	Propagation delay Dna or Dnb to Qn (other input High)	Waveform 2	3.5 3.0	5.3 4.7	7.0 6.5	3.5 3.0	8.0 7.5	3.5 3.0	10.0 8.0	ns

AC WAVEFORMS

For all waveforms, $V_M = 1.5V$.

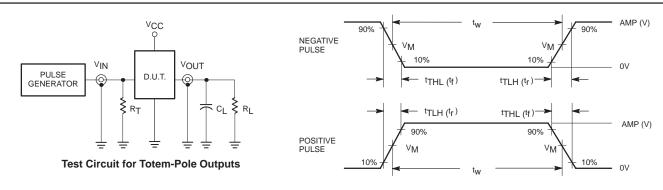


Waveform 1. Propagation Delay for Non-Inverting Outputs



Waveform 2. Propagation Delay for Inverting Outputs

TEST CIRCUIT AND WAVEFORMS



DEFINITIONS:

R_L = Load resistor;

see AC ELECTRICAL CHARACTERISTICS for value. Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.

Termination resistance should be equal to Z_{OUT} of

pulse generators.

Input Pulse Definition

family	INP	INPUT PULSE REQUIREMENTS										
	amplitude	V_{M}	rep. rate	t _w	t _{TLH}	t _{THL}						
74F	3.0V 1.		1MHz	500ns	2.5ns	2.5ns						

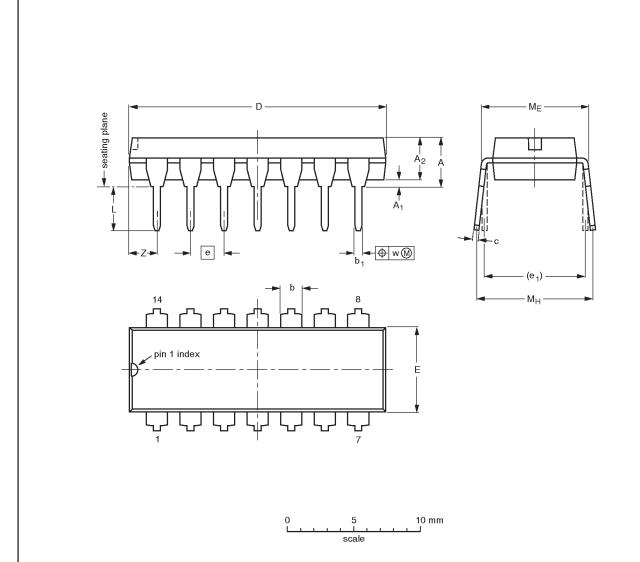
SF00006

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DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT27-1	050G04	MO-001AA				92-11-17 95-03-11	

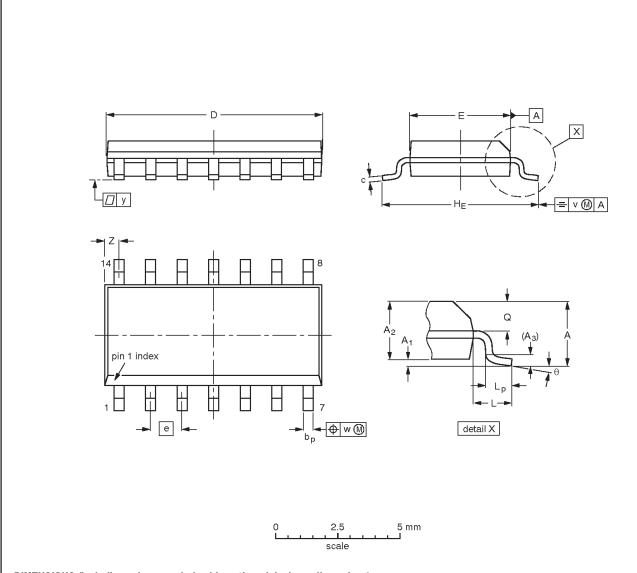
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SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁	A ₂	А3	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.35 0.34	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT108-1	076E06S	MS-012AB				-95-01-23- 97-05-22

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Philips Semiconductors Product specification

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NOTES

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Data sheet status

Data sheet status	Product status	Definition [1]	
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.	
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.	
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product	

^[1] Please consult the most recently issued datasheet before initiating or completing a design.

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